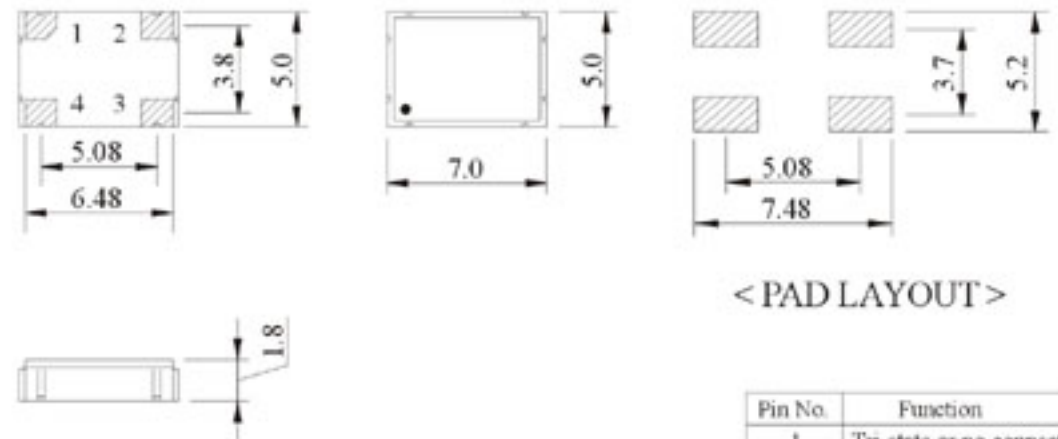


**Voltage Controlled Crystal Oscillator (VCXO)**
**电压控制晶体振荡器**
**CERAMIC SMD VCXO**
**DIMENSIONS(Unit:mm) 外形尺寸**

Low Height  
High Speed CMOS  
Set Top Box  
CCD System

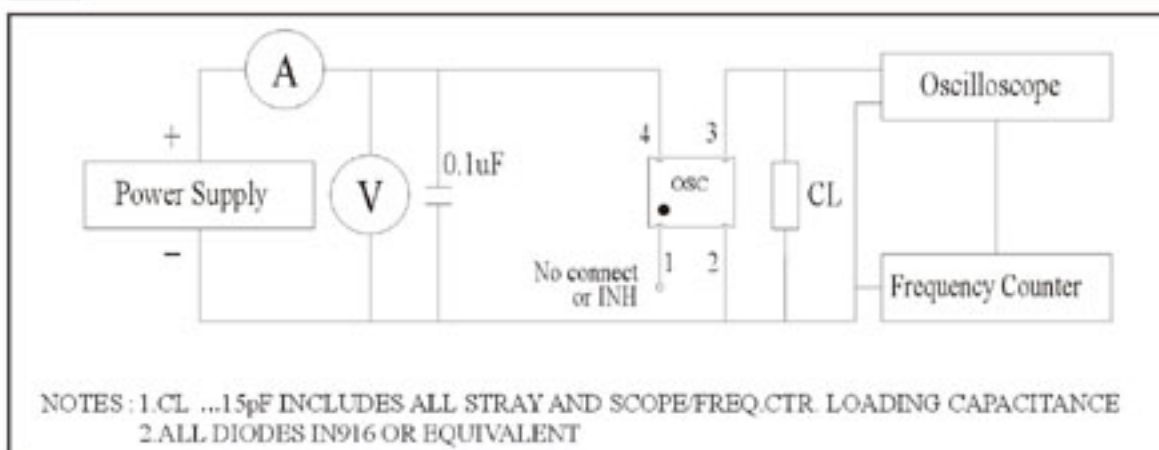
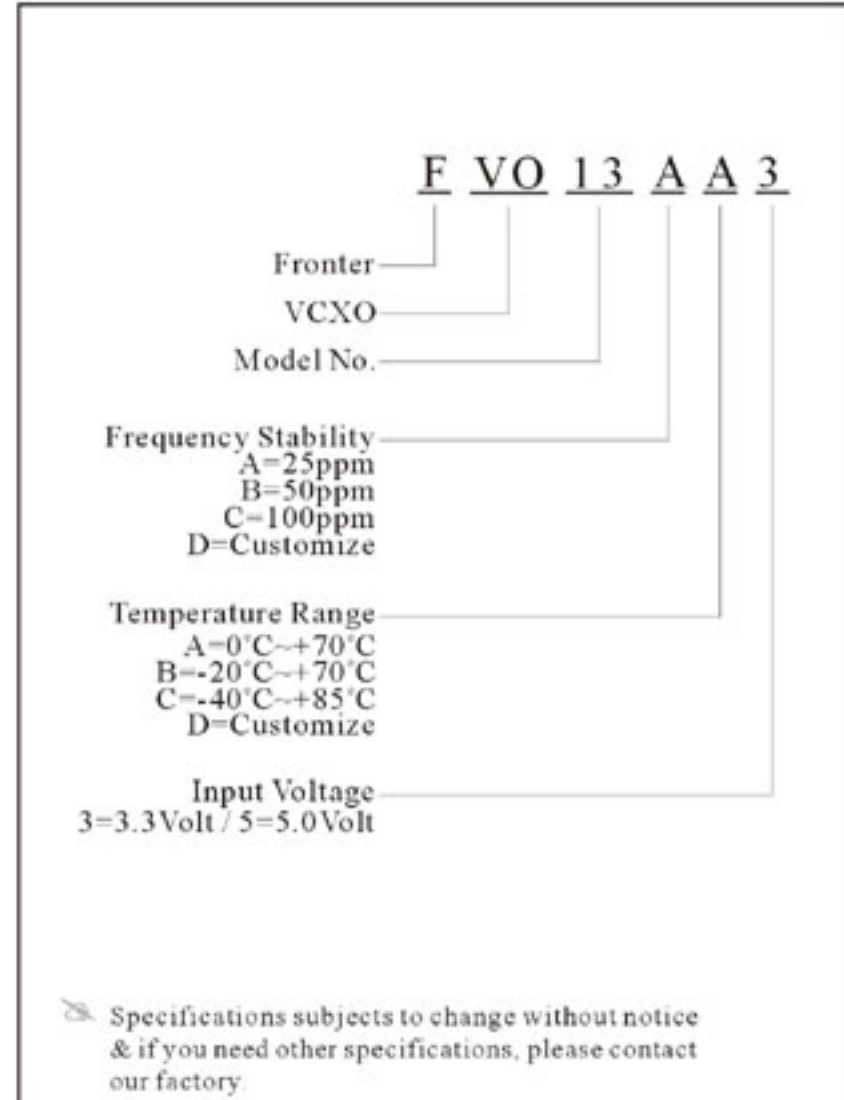

**< PAD LAYOUT >**

| Pin No. | Function                |
|---------|-------------------------|
| 1       | Tri-state or no connect |
| 2       | GND                     |
| 3       | Frequency output        |
| 4       | Vcc                     |

**PARAMETERS 技术参数 (FVO 13 Series)**

| ELECTRICAL SPECIFICATIONS   |   |   |
|-----------------------------|---|---|
| Frequency Range 频率范围        | 1.000MHz to 125.000MHz  |   |
| Frequency Stability 频率稳定度   | ± 25ppm   | ± 50ppm   |
|                             | ± 100ppm (Standard)<br>Inclusive of operating temperature range |   |
| Operating Temperature Range | 0°C~+70°C   |   |
| Storage Temperature Range   | -40°C~+85°C   |   |
| Input Voltage 输入电压          | +5Vdc ± 0.5V  | +3.3Vdc ± 0.3V                                  |
| Input Current 输入电流          | 60mA max.   | 40mA max.                                       |
| O/I Level O/I 电平            | +0.5V max./+4.5V min.   | +0.4V max./+3.0V min.                           |
| Pull Ability 压控范围           | ± 100ppm min. (Typical)<br>(At 2.5Volt 2V)                      | ± 100ppm min. (Typical)<br>(At 1.65Volts 1.35V) |
| Linearity 线性度               | ± 10% max. (Typical)  | ± 30% max. (Typical)                            |
| Symmetry 占空比                | 60/40% or 40/60% (Typical)                                      |   |
| Rise & Fall time 上升和下降时间    | 10nS max.   |   |
| Start up time 起振时间          | 10mS max.   |   |
| Fan out 输出负载                | 15pF//10TTL   |   |
| Aging (at 25 °C) 老化率        | ± 5ppm / Year max   |   |

| ENVIRONMENTAL & MECHANICAL SPECIFICATIONS |   |
|---|---|
| Shock 抗冲击性能                               | FIL-STD-883C, Method 2002, Condition B      |
| Vibration 抗振性能                            | FIL-STD-883C, Method 2007, Condition A      |
| Solderability 焊接性能                        | FIL-STD-883C, Method 2003                   |
| Seal Integrity 密封性能                       | FIL-STD-883C, Method 1014, Condition C & A2 |
| Marking 标记                                | FIL-STD-883C, Method 215                    |

**TEST CIRCUIT 测试原理图**

**PART NUMBER GUIDE**

**WAVE FORM 波形图**
